Se	arcn Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/043,273	PAEK, SEUNG-KYU	
Examiner	Art Unit	
Hung Q. Dang	2621	

SEARCHED					
Class	Subclass	Date	Examiner		
386	49, 77, 81- 83, 95, 105-106	8/16/2007	НОД		
370	360	8/16/2007	HQD		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	-			
		•		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor's Name Search	6/29/2006	HQD
STIC Plus Search	6/20/2007	НФР
USPAT; US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB (see Search History attached)	6/21/2006- 7/06/2007, 4/26/2007	НОД
<u> </u>		